Unit: mm

TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π–MOSIII)

## 2SK2700

# Chopper Regulator, DC–DC Converter and Motor Drive Applications

 $\begin{array}{ll} \bullet & Low\ drain-source\ ON\ resistance & :\ RDS\ (ON) = 3.7\ \Omega\ (typ.) \\ \bullet & High\ forward\ transfer\ admittance & :\ |\ Y_{fs}| = 2.6\ S\ (typ.) \\ \bullet & Low\ leakage\ current & :\ IDSS = 100\ \mu A\ (max)\ (VDS = 720\ V) \\ \bullet & Enhancement\ mode & :\ V_{th} = 2.0{\sim}4.0\ V\ (VDS = 10\ V,\ ID = 1\ mA) \end{array}$ 

#### Absolute Maximum Ratings (Ta = 25°C)

Characteris	stics	Symbol	Rating	Unit
Drain-source voltage		$V_{DSS}$	900	V
Drain-gate voltage (Ro	<sub>SS</sub> = 20 kΩ)	$V_{DGR}$	900	V
Gate-source voltage		V <sub>GSS</sub>	±30	V
Drain current	DC (Note 1)	I <sub>D</sub>	3	Α
	Pulse (Note 1)	I <sub>DP</sub>	9	Α
Drain power dissipation	n (Tc = 25°C)	PD	40	W
Single pulse avalanche	e energy (Note 2)	E <sub>AS</sub>	295	mJ
Avalanche current		I <sub>AR</sub>	3	Α
Repetitive avalanche e	nergy (Note 3)	E <sub>AR</sub>	4	mJ
Channel temperature		T <sub>ch</sub>	150	°C
Storage temperature range		T <sub>stg</sub>	-55~150	°C

Weight: 1.9 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

#### **Thermal Characteristics**

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R <sub>th (ch-c)</sub>	3.125	°C/W
Thermal resistance, channel to ambient	R <sub>th (ch-a)</sub>	62.5	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2:  $V_{DD}$  = 90 V,  $T_{ch}$  = 25°C (initial), L = 60.0 mH,  $R_{G}$  = 25  $\Omega$ ,  $I_{AR}$  = 3 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device.

Please handle with caution.



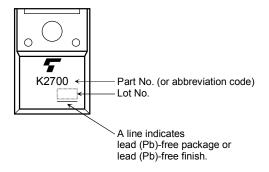
## Electrical Characteristics (Ta = 25°C)

Charac	eteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	rrent	I <sub>GSS</sub>	V <sub>GS</sub> = ±30 V, V <sub>DS</sub> = 0 V		_	±10	μA
Gate-source bre	eakdown voltage	V (BR) GSS	I <sub>G</sub> = ±10 μA, V <sub>DS</sub> = 0 V	±30	_	_	V
Drain cut-off cu	rrent	I <sub>DSS</sub>	V <sub>DS</sub> = 720 V, V <sub>GS</sub> = 0 V	_	_	100	μΑ
Drain-source br	eakdown voltage	V (BR) DSS	I <sub>D</sub> = 10 mA, V <sub>GS</sub> = 0 V	900	_	_	V
Gate threshold v	oltage	V <sub>th</sub>	V <sub>DS</sub> = 10 V, I <sub>D</sub> = 1 mA	2.0	_	4.0	V
Drain-source Ol	N resistance	R <sub>DS (ON)</sub>	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 1.5 A	_	3.7	4.3	Ω
Forward transfer	admittance	Y <sub>fs</sub>	V <sub>DS</sub> = 20 V, I <sub>D</sub> = 1.5 A	0.65	2.6	_	S
Input capacitano	e	C <sub>iss</sub>			750	_	
Reverse transfer	r capacitance	C <sub>rss</sub>	V <sub>DS</sub> = 25 V, V <sub>GS</sub> = 0 V, f = 1 MHz	_	10	_	pF
Output capacital	utput capacitance C <sub>oss</sub>		_	70	_		
Switching time	Rise time	t <sub>r</sub>	$V_{GS} \stackrel{10V}{\circ}_{0V} \stackrel{I_{D}=1.5A}{\longrightarrow}_{R_{L}=133\Omega} \circ V_{out}$ $V_{DD} \stackrel{\vdots}{=} 200V$ $Duty \leq 1\%, \ t_{W}=10\mu s$	_	15	_	
	Turn-on time	t <sub>on</sub>		_	55	_	nc
	Fall time	t <sub>f</sub>		_	30	_	ns
	Turn-off time	t <sub>off</sub>		_	110	_	
Total gate charg plus gate–drain)	· · · · · · · · · · · · · · · · · · ·			25	_		
Gate-source charge		Q <sub>gs</sub>	$V_{DD} \approx 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 3 \text{ A}$		13	_	nC
Gate-drain ("miller") Charge		$Q_{gd}$			12	_	

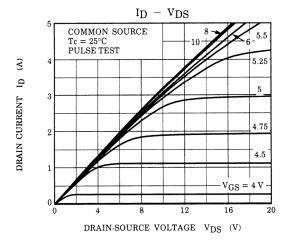
### Source-Drain Ratings and Characteristics (Ta = 25°C)

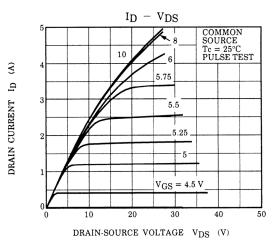
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I <sub>DR</sub>	_	_	-	3	Α
Pulse drain reverse current (Note 1)	I <sub>DRP</sub>	_	_	_	9	Α
Forward voltage (diode)	V <sub>DSF</sub>	I <sub>DR</sub> = 3 A, V <sub>GS</sub> = 0 V	_	_	-1.9	V
Reverse recovery time	t <sub>rr</sub>	I <sub>DR</sub> = 3 A, V <sub>GS</sub> = 0 V	_	1100		ns
Reverse recovery charge	Q <sub>rr</sub>	dl <sub>DR</sub> / dt = 100 A / μs	_	7.2	_	μC

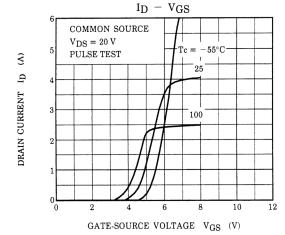
## Marking

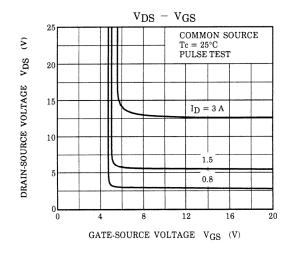


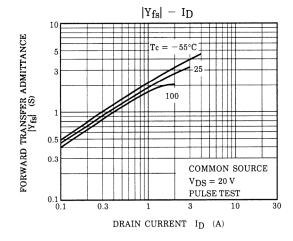
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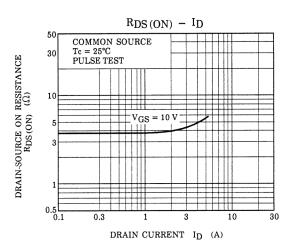


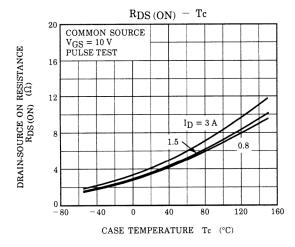


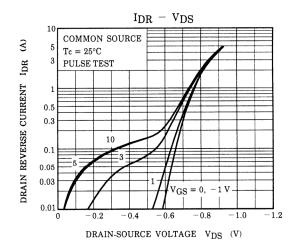


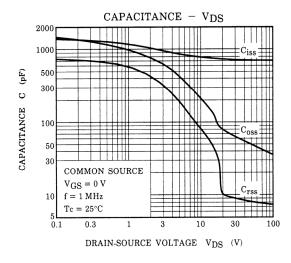


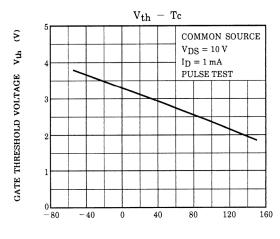


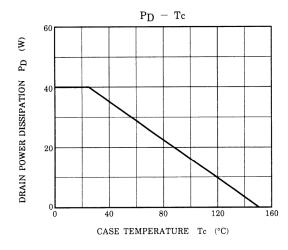


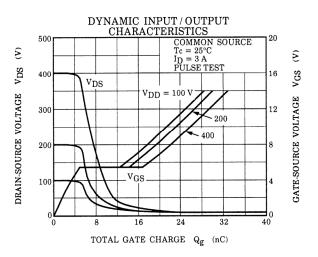




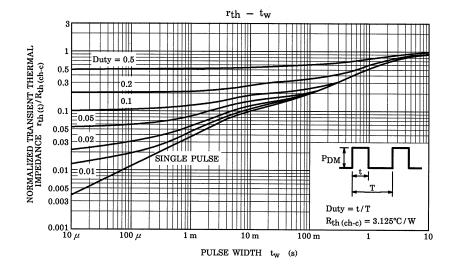


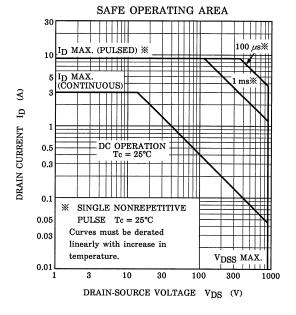


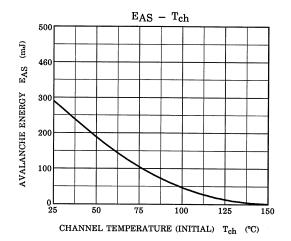


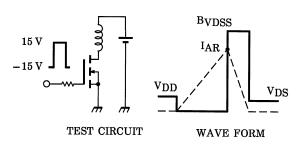


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$$R_G$$
 = 25  $\Omega$   
 $V_{DD}$  = 90 V, L = 60 mH

$$EAS = \frac{1}{2} \cdot L \cdot I^2 \cdot \left( \frac{BVDSS}{BVDSS - VDD} \right)$$

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